

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application.

Listing of Claims:

Claims 1-33 (Canceled)

Claim 34 (Previously presented): A test head assembly comprising:

a probe card;
a contactor; and
an interposer interconnecting said probe card and said contactor,
wherein said interposer comprises a first plurality of spring contacts, each of said first plurality of spring contacts comprising a beam extending away from a first surface of said interposer, and
wherein said beam is contoured to affect a deflection characteristic of said beam.

Claim 35 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured along a length of said beam.

Claim 36 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured to increase a bending moment of said beam.

Claim 37 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured to increase an elastic range of said beam.

Claim 38 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured to increase an elastic deflection ratio of said beam.

Claim 39 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured to increase an area moment of inertia of said beam.

Claim 40 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured to stiffen said beam.

Claim 41 (Previously presented): The test head assembly of claim 34, wherein said beam is corrugated.

Claim 42 (Previously presented): The test head assembly of claim 34, wherein said beam is contoured along a cross-sectional width thereof.

Claim 43 (Previously presented): The test head assembly of claim 42, wherein said cross-sectional width is "V" shaped.

Claim 44 (Previously presented): The test head assembly of claim 42, wherein said cross-sectional width comprises a rib.

Claim 45 (Previously presented): The test head assembly of claim 34, wherein said beam is serpentine shaped.

Claim 46 (Previously presented): The test head assembly of claim 34, wherein said interposer further comprises a second plurality of spring contacts, each of said second plurality of spring contacts comprising a contoured beam extending away from a second surface of said interposer.

Claims 47-50 (Canceled)

Claim 51 (Previously presented): A test head assembly comprising:
a probe card;
a contactor; and
a first plurality of spring contacts interconnecting said probe card and said contactor,
wherein each of said first plurality of spring contacts comprises a beam contoured to
affect a deflection characteristic of said beam.

Claim 52 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured along a length of said beam.

Claim 53 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured to increase a bending moment of said beam.

Claim 54 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured to increase an elastic range of said beam.

Claim 55 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured to increase an elastic deflection ratio of said beam.

Claim 56 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured to increase an area moment of inertia of said beam.

Claim 57 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured to stiffen said beam.

Claim 58 (Previously presented): The test head assembly of claim 51, wherein said beam is
corrugated.

Claim 59 (Previously presented): The test head assembly of claim 51, wherein said beam is
contoured along a cross-sectional width thereof.

Claim 60 (Previously presented): The test head assembly of claim 59, wherein said cross-sectional width is "V" shaped.

Claim 61 (Previously presented): The test head assembly of claim 59, wherein said cross-sectional width is "U" shaped.

Claim 62 (Previously presented): The test head assembly of claim 59, wherein said cross-sectional width comprises a rib.

Claim 63 (Previously presented): The test head assembly of claim 51, wherein said beam is serpentine shaped.

Claim 64 (Previously presented): The test head assembly of claim 51 further comprising a second plurality of spring contacts disposed on said contactor to contact an electronic device to be tested, wherein each of said second plurality of spring contacts comprising a contoured beam,

Claims 65-68 (Canceled):

Claim 69 (New and withdrawn): The test head assembly of claim 34, wherein each of said spring contacts comprises a plurality of beams.

Claim 70 (New and withdrawn): The test head assembly of claim 51, wherein each of said spring contacts comprises a plurality of beams.

Claim 71 (New): The test head assembly of claim 42, wherein said cross-sectional width is "U" shaped.